

**Search Notes**

Application/Control No.

10/699,613

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

DELEULE, ARNAUD

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	10,19	11/1/2005	PK
700	116,221	11/1/2005	PK
700	225	11/1/2005	PK
326	38,41,47	11/1/2005	PK
326	101	11/1/2005	PK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST)—USPAT, USPGPUB Cl/Sub searched: 716/1-21; 700/115- 116,221-222,224-227; 326/38-50,101- 103; 438/6-10 (see attach)	11/1/2005	PK
-EPO, JPO, IBM TDB, Derwent (see attached)	11/1/2005	PK
IEE/IEEE Xplore (see attached)	11/1/2005	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner